



## DOCUMENT CHANGE REQUEST

DCR number 1079 Changes required for: General

Date: 2017/05/24

Date sent: 2017/03/29

Status: IMPLEMENTED

Originator: Steve Thacker

Organisation: ESCC Executive  
Secretariat

Title: Transistors Matched Dual PNP, based on types 2N3810 and 2N3811

Number: 5207/005

Issue: 4

Other documents affected:

Page:

12, 14

Paragraph:

2.4.1, 2.4.2

Original wording:

Para. 2.4.1:  $V_{BE(sat)2}$ : test condition:  $I_B = -100\text{mA}$

Para. 2.4.2:  $|V_{BE1}-V_{BE2}|T_{amb}|1$ : test condition:  $I_C = -100\text{mA}$

Proposed wording:


Amend test conditions as follows (i.e. change mA to A):

Para. 2.4.1:  $V_{BE(sat)2}$ : test condition:  $I_B = -100\text{A}$  (microamps)

Para. 2.4.2:  $|V_{BE1}-V_{BE2}|T_{amb}|1$ : test condition:  $I_C = -100\text{A}$  (microamps)

Justification:

typographic error in previous revision.

Attachments:
N/A
Modifications:
N/A
Approval signature:

Date signed:
2017-05-24